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| Notice of References Cited | Application/Control No. 10/529,880 | Applicant(s)/Patent Under Reexamination YAOI ET AL. | |
| | Examiner MICHAEL T. TRAN | Art Unit 2827 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| * | A | US-4,882,707 | -11-1989 | Mizutani, Yoshihisa | 365/185.12 |
| * | B | US-4,933,907 | 06-1990 | Kumanoya et al. | 365/222 |
| * | C | US-5,963,467 | 10-1999 | Miyatake et al. | 365/149 |
| * | D | US-6,343,044 | 01-2002 | Hsu et al. | 365/227 |
| * | E | US-6,683,491 | 01-2004 | Koga et al. | 327/544 |
| * | F | US-5,931,951 | 08-1999 | Ando, Motoaki | 713/324 |
| * | G | US-5,623,677 | 04-1997 | Townsley et al. | 713/310 |
| * | H | US-6,775,784 | 08-2004 | Park, Seong-Geun | 713/320 |
| * | I | US-5,974,551 | 10-1999 | Lee, Kyung-Sang | 713/300 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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